Brukerナノインデンターユーザー対象

年末特別キャンペーンのご案内

年末特別キャンペーン

ブルカーナノインデンターをご愛顧いただいておりますお客様へ、ご使用のナノインデンターの圧子をお得に購入できるプランを準備いたしました。是非この機会にご検討をお願い致します。

期間　　：～ 2026年12月18日(金)迄
対象　　：下記リスト記載の圧子
キャンペーン内容：25%OFF

※数量限定かつ先着順になります。ご興味のある圧子については弊社までお問い合わせください。

PART NUMBER	PROBE	DESCRIPTION
プラットフォーム型ナノインデンター用		
標準ヘッド用		
TI-0041	Conical, 20 µm tip radius, 90° cone angle	Conical diamond probe
TI-0042	Conical, 50 µm tip radius, 90° cone angle	Conical diamond probe
TI-0051	NorthStar™ cube corner, <40 nm tip radius, 90° included angle	Three-sided pyramidal diamond probe
TI-0068	Sapphire flat punch, 1 mm diameter	Cylindrical flat-punch sapphire probe
TI-0102	Titanium flat punch, 500 µm diameter	Cylindrical flat-punch titanium probe
TI-0145	Flat-ended conical, 10 µm diameter, 60° cone angle	Flat-ended conical diamond probe
TI-0177	Flat-ended conical, 20 µm diameter, 60° cone angle	Flat-ended conical diamond probe
高荷重ヘッド用		
TI-0053	Fluid-cell Berkovich, 100 nm tip radius, 142.3° included angle	Three-sided pyramidal diamond probe
TI-0077	Fluid-cell conical, 100 µm tip radius, 90° cone angle	Conical diamond probe
TI-0096	Fluid-cell conical, 20 µm tip radius, 90° cone angle	Conical diamond probe
TI-0164	Fluid-cell flat-ended conical, 50 µm diameter, 60° cone angle	Flat-ended conical diamond probe
TI-0199	High-load fluid-cell flat-ended conical, 100 µm diameter, 60° cone angle	Flat-ended conical diamond probe
TI-0204	Fluid-cell conical, 10 µm tip radius, 90° cone angle	Conical diamond probe
TI-0228	Fluid-cell titanium flat punch, 500 µm diameter	Cylindrical flat-punch titanium probe
TI-0305	Fluid-cell sapphire spherical probe, 400 µm diameter	Spherical sapphire probe
ECRオプション用		
TI-0162	Pulsar-D ECR conductive diamond Berkovich	Three-sided pyramidal diamond nanoECR probe
加熱ステージ用		
TI-0270	xSol 17 CBN Berkovich	Three-sided pyramidal CBN probe
TI-0271	xSol 17 diamond Berkovich	Three-sided pyramidal diamond probe
TI-0276	High-load xSol 17 sapphire Berkovich	Three-sided pyramidal sapphire probe
TI-0277	High-load xSol 17 diamond Berkovich	Three-sided pyramidal diamond probe
TI-0290	xSol 25 sapphire Berkovich	Three-sided pyramidal sapphire probe
TI-0296	High-load xSol 25 sapphire Berkovich	Three-sided pyramidal sapphire probe
in SEM/TEM ナノインデンター用		
室温試験用		
TI-0261	PicoIndenter flat-ended conical, 20 µm diameter, 60° cone angle	Flat-ended conical diamond probe
TI-0275	PicoIndenter flat-ended conical, 5 µm diameter, 60° cone angle	Flat-ended conical diamond probe
TI-0300	PicoIndenter conical, 1 µm tip radius, 60° cone angle	Conical diamond probe
TI-0302	PicoIndenter conical, 10 µm tip radius, 60° cone angle	Conical diamond probe
TI-0303	PicoIndenter conical, 20 µm tip radius, 60° cone angle	Conical diamond probe
TI-0311	PicoIndenter rough conical FIB stock	Conical diamond probe
加熱試験用		
TI-0307	PicoIndenter 800° C cube corner	Three-sided pyramidal diamond probe
TI-0308	PicoIndenter 800° C flat-ended conical, 10 µm diameter, 60° cone angle	Flat-ended conical diamond probe
TI-0310	PicoIndenter 800° C rough conical FIB stock	Conical diamond probe
TI-0314	PicoIndenter 1000° C CBN Berkovich	Three-sided pyramidal CBN probe
電気測定用		
TI-0288	PicoIndenter conductive ECM cube corner	Three-sided pyramidal conductive diamond probe

ブルカージャパン株式会社
ナノ表面計測事業部

【お問合せ】
〒104-0033　東京都中央区新川1-4-1
Tel:03-3523-6361　FAX:03-3523-6364
Email: Info-nano.BNS.JP@bruker.com / Web：www.bruker-nano.jp